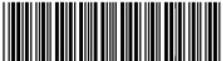


Search Notes



Application/Control No.

10/564, 108

Examiner

PIRA LEE

**Applicant(s)/Patent under
Reexamination**

RAZAVI ET AL.

SEARCHED

SEARCHED

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner